

Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D  
Characterisation and Imaging with Ion Beams | (smr 2856)

Contribution ID : 23

Type : **not specified**

## Case study (II) - Nanomaterials

*Friday, 30 September 2016 08:30 (1:00)*

### Content

This lecture will show case examples of MEIS and IBA applied to materials science, demonstrating the capabilities of the techniques in demanding situations.

### Summary

**Presenter(s)** : GRANDE, Pedro L.

**Session Classification** : DAY 5